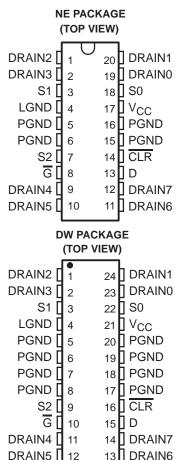
- Low r_{DS(on)} . . . 1 Ω Typ
- Output Short-Circuit Protection
- Avalanche Energy . . . 75 mJ
- Eight 350-mA DMOS Outputs
- 50-V Switching Capability
- Four Distinct Function Modes
- Low Power Consumption

description

This power logic 8-bit addressable latch controls open-drain DMOS-transistor outputs and is designed for general-purpose storage applications in digital systems. Specific uses include working registers, serial-holding registers, and decoders or demultiplexers. This is a multifunctional device capable of operating as eight addressable latches or an 8-line demultiplexer with active-low DMOS outputs. Each open-drain DMOS transistor features an independent chopping current-limiting circuit to prevent damage in the case of a short circuit.

Four distinct modes of operation are selectable by controlling the clear (\overline{CLR}) and enable (\overline{G}) inputs as enumerated in the function table. In the addressable-latch mode, data at the data-in (D) terminal is written into the addressed latch. The addressed DMOS-transistor output inverts the data input with all unaddressed DMOS-transistor outputs remaining in their previous states. In the memory mode, all DMOS-transistor outputs remain in their previous states and are unaffected by the data or address inputs. To eliminate the possibility of entering erroneous data in the latch, enable G should be held high (inactive) while the address lines are changing. In the 8-line demultiplexing mode, the addressed output is inverted with respect to the D input and all other outputs are high. In the clear mode, all outputs are high and unaffected by the address and data inputs.

Separate power ground (PGND) and logic ground (LGND) terminals are provided to facilitate maximum system flexibility. All PGND terminals are internally connected, and each PGND terminal must be externally connected to the power system ground in order to minimize parasitic impedance. A single-point connection between LGND and PGND must be made externally in a manner that reduces crosstalk between the logic and load circuits.



FUNCTION TABLE

INPUTS			OUTPUT OF ADDRESSED	EACH OTHER	FUNCTION
CLR	G	D	DRAIN	DRAIN	lononon
H H	L L	H L	L H	Q _{io} Q _{io}	Addressable Latch
Н	Н	Χ	Q _{io}	Q _{io}	Memory
L L	L L	H L	L H	H	8-Line Demultiplexer
L	Н	Χ	Н	Н	Clear

LATCH SELECTION TABLE

SELE	CT IN	DRAIN	
S2	S1	S0	ADDRESSED
L	L	L	0
L	L	Н	1
L	Н	L	2
L	Н	Н	3
Н	L	L	4
Н	L	Н	5
Н	Н	L	6
Н	Н	Н	7

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

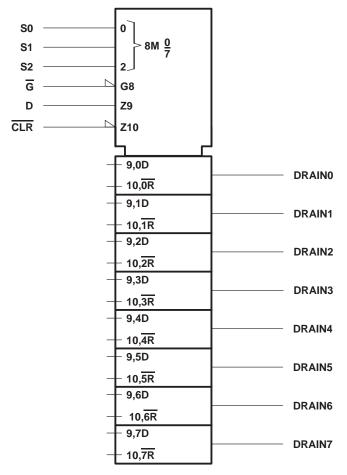


SLIS004B - APRIL 1993 - REVISED SEPTEMBER 1995

description (continued)

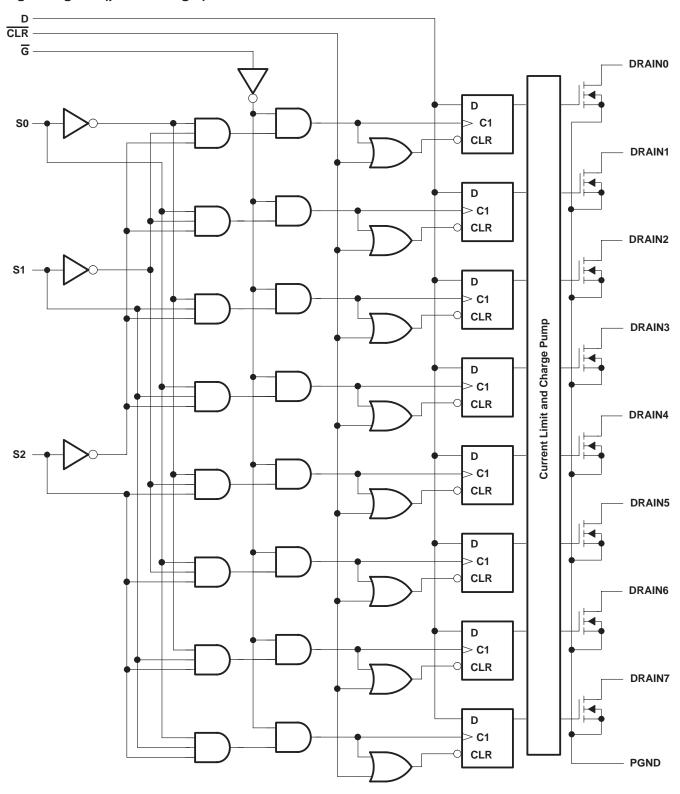
The TPIC6A259 is offered in a thermally-enhanced dual-in-line (NE) package and a wide-body, surface-mount (DW) package. The TPIC6A259 is characterized for operation over the operating case temperature range of -40° C to 125° C.

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

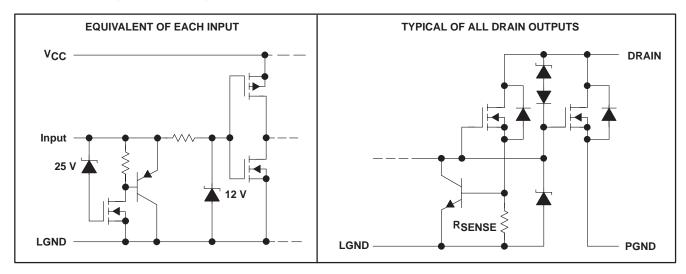
logic diagram (positive logic)





SLIS004B - APRIL 1993 - REVISED SEPTEMBER 1995

schematic of inputs and outputs



absolute maximum ratings over the recommended operating case temperature range (unless otherwise noted) $\!\!\!\!\!^{\dagger}$

Logic supply voltage, V _{CC} (see Note 1)	7 V
Logic input voltage range, V _I	0.3 V to 7 V
Power DMOS drain-to-source voltage, V _{DS} (see Note 2)	50 V
Continuous source-to-drain diode anode current	
Pulsed source-to-drain diode anode current (see Note 3)	2 A
Pulsed drain current, each output, all outputs on, I_D , $T_C = 25^{\circ}C$ (see Note 3).	1.1 A
Continuous drain current, each output, all outputs on, I_D , $T_C = 25^{\circ}C$	350 mA
Peak drain current single output, T _C = 25°C (see Note 3)	1.1 A
Single-pulse avalanche energy, EAS (see Figure 6)	75 mJ
Avalanche current, I _{AS} (see Note 4)	600 mA
Continuous total dissipation	See Dissipation Rating Table
Operating virtual junction temperature range, T _J	–40°C to 150°C
Operating case temperature range, T _C	–40°C to 125°C
Storage temperature range, T _{stq}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values are with respect to LGND and PGND.
 - 2. Each power DMOS source is internally connected to PGND.
 - 3. Pulse duration \leq 100 μ s, and duty cycle \leq 2%.
 - 4. DRAIN supply voltage = 15 V, starting junction temperature (T_{JS}) = 25°C, L = 210 mH, and I_{AS} = 600 mA (see Figure 6).

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize C}} \leq 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR ABOVE T _C = 25°C	T _C = 125°C POWER RATING
DW	1750 mW	14 mW/°C	350 mW
NE	2500 mW	20 mW/°C	500 mW



recommended operating conditions

	MIN	MAX	UNIT
Logic supply voltage, V _{CC}	4.5	5.5	V
High-level input voltage, VIH	0.85 V _C C	VCC	V
Low-level input voltage, V _{IL}	0	0.15 V _{CC}	V
Pulsed drain output current, T _C = 25°C, V _{CC} = 5 V (see Notes 3 and 5)	-1.8	0.6	Α
Setup time, D high before G↑,t _{SU} (see Figure 2)	10		ns
Hold time, D high before $\overline{G} \uparrow$, t _h (see Figure 2)	5		ns
Pulse duration, t _W (see Figure 2)	15		ns
Operating case temperature, T _C	-40	125	°C

electrical characteristics, V_{CC} = 5 V, T_{C} = 25°C (unless otherwise noted)

	PARAMETER	-	MIN	TYP	MAX	UNIT		
V _{(BR)DSX}	Drain-to-source breakdown voltage	I _D = 1 mA			50			V
V _{SD}	Source-to-drain diode forward voltage	I _F = 350 mA,	See Note 3			0.8	1.1	V
lн	High-level input current	VI = VCC					1	μΑ
I _{IL}	Low-level input current	V _I = 0	V _I = 0				-1	μΑ
ICC	Logic supply current	$I_O = 0$, $V_I = V_{CC}$ or 0				0.5	5	mA
lok	Output current at which chopping starts	T _C = 25°C, See Note 5 and Figures 3 and 4			0.6	0.8	1.1	А
I _(nom)	Nominal current	V _{DS(on)} = 0.5 V, V _{CC} = 5 V,	V _{DS(on)} = 0.5 V, I _(nom) = I _D , T _C = 85°C, V _{CC} = 5 V, See Notes 5, 6, and 7			350		mA
1_			= 40 V, T _C = 25°C			0.1	1	^
ID	Off-state drain current	$V_{DS} = 40 \text{ V},$	T _C = 125°C			0.2	5	μΑ
r · ·	Static drain-to-source on-state	$I_D = 350 \text{ mA},$	$T_C = 25^{\circ}C$	See Notes 5 and 6		1	1.5	Ω
^r DS(on)	resistance	$I_D = 350 \text{ mA},$	T _C = 125°C	and Figures 9 and 10	·	1.7	2.5	22

switching characteristics, V_{CC} = 5 V, T_{C} = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
tPHL	Propagation delay time, high- to low-level output from D			30		ns
tPLH	Propagation delay time, low- to high-level output from D	$C_L = 30 \text{ pF}, \qquad I_D = 350 \text{ mA},$		125		ns
t _r	Rise time, drain output	See Figures 1, 2, and 11		60		ns
tf	Fall time, drain output			30		ns
ta	Reverse-recovery-current rise time	$I_F = 350 \text{ mA}, \qquad \text{di/dt} = 20 \text{ A/}\mu\text{s},$		100		ns
t _{rr}	Reverse-recovery time	See Notes 5 and 6 and Figure 5		300		ns

NOTES: 3. Pulse duration \leq 100 μ s and duty cycle \leq 2%.

- 5. Technique should limit T_J T_C to 10°C maximum.
- 6. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.
- Nominal current is defined for a consistent comparison between devices from different sources. It is the current that produces a voltage drop of 0.5 V at T_C = 85°C.

thermal resistance

	PARAMETER	TEST CONDITIONS			MAX	UNIT	
D	The second resistance is unation to see	DW	All sight sutputs with a such passes		10	0000	
$R_{\theta JC}$	Thermal resistance, junction-to-case	NE	All eight outputs with equal power		10	°C/W	
_	The control of the control of the control of	DW	All sinks and other will a small and a		50	0000	
$R_{\theta JA}$	Thermal resistance, junction-to-ambient		All eight outputs with equal power		50	°C/W	



PARAMETER MEASUREMENT INFORMATION

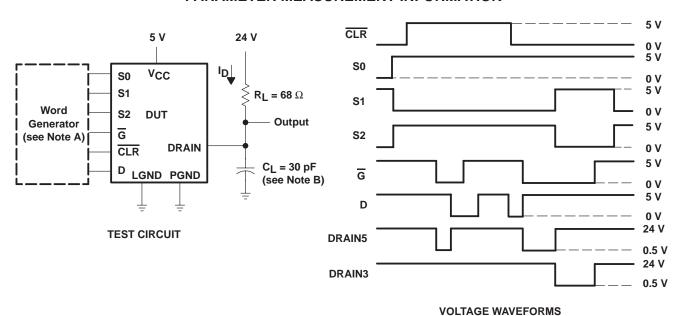


Figure 1. Typical Operation Mode

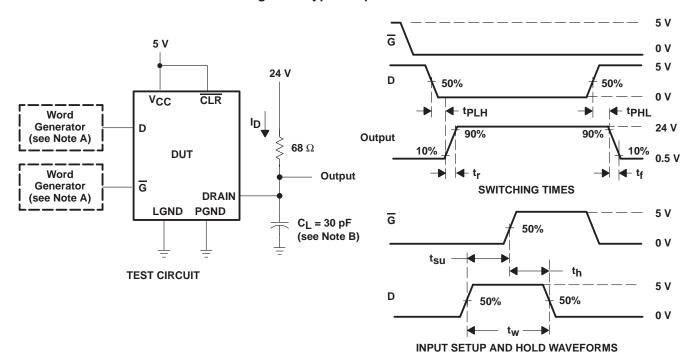


Figure 2. Test Circuit, Switching Times, and Voltage Waveforms

- NOTES: A. The word generator has the following characteristics: $t_{\Gamma} \le 10$ ns, $t_{W} = 300$ ns, pulsed repetition rate (PRR) = 5 kHz, $Z_{Q} = 50 \ \Omega$.
 - B. C_L includes probe and jig capacitance.



PARAMETER MEASUREMENT INFORMATION

TIME FOR INCREASING LOAD RESISTANCE 1.5 1.25 1.25 0.75 0.5 0.25

First output current pulses after turn-on in chopping mode with resistive load.

Time

NOTES: A. Figure 3 illustrates the output current characteristics of the device energizing a load having initially low, increasing resistance, e.g., an incandescent lamp. In region 1, chopping occurs and the peak current is limited to I_{OK}. In region 2, output current is continuous. The same characteristics occur in reverse order when the device energizes a load having an initially high, decreasing resistance.

Region 2

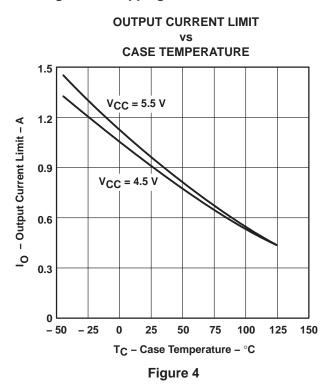
B. Region 1 duty cycle is approximately 2%.

Time

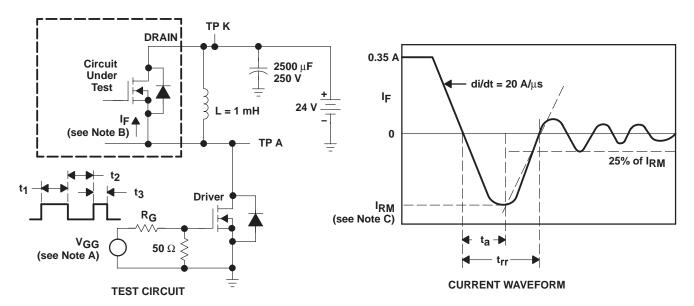
Region 1

0

Figure 3. Chopping-Mode Characteristics

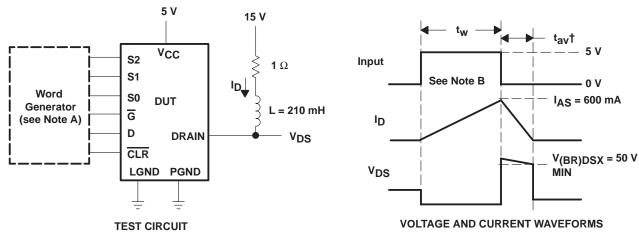


PARAMETER MEASUREMENT INFORMATION



- NOTES: A. The V_{GG} amplitude and R_G are adjusted for di/dt = 20 A/µs. A V_{GG} double-pulse train is used to set I_F = 0.35 A, where t₁ = 10 µs, $t_2 = 7 \mu s$, and $t_3 = 3 \mu s$.
 - B. The DRAIN terminal under test is connected to the TP K test point. All other terminals are connected together and connected to the TP A test point.
 - C. I_{RM} = maximum recovery current

Figure 5. Reverse-Recovery-Current Test Circuit and Waveforms of Source-Drain Diode



† Non-JEDEC symbol for avalanche time.

NOTES: A. The word generator has the following characteristics: $t_r \le 10$ ns, $t_f \le 10$ ns, $t_O = 50 \Omega$.

B. Input pulse duration, t_W , is increased until peak current IAS = 600 mA. Energy test level is defined as $E_{AS} = (I_{AS} \times V_{(BR)DSX} \times t_{av})/2 = 75 \text{ mJ}.$

Figure 6. Single-Pulse Avalanche Energy Test Circuit and Waveforms



TYPICAL CHARACTERISTICS

MAXIMUM CONTINUOUS DRAIN CURRENT OF EACH OUTPUT

NUMBER OF OUTPUTS CONDUCTING **SIMULTANEOUSLY**

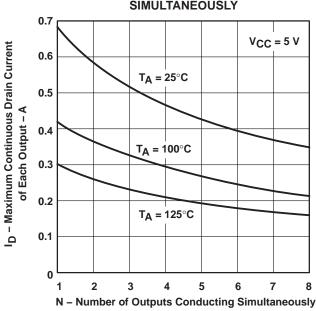


Figure 7

OF EACH OUTPUT

MAXIMUM PEAK DRAIN CURRENT

NUMBER OF OUTPUTS CONDUCTING SIMULTANEOUSLY

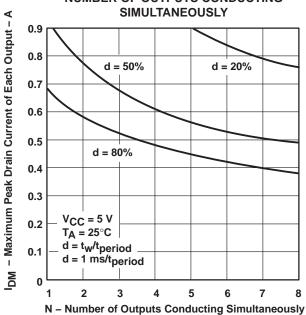
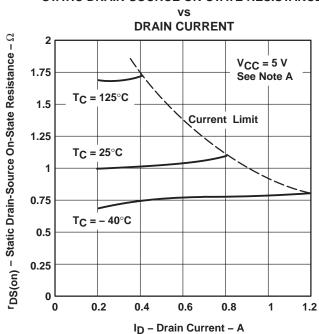


Figure 8

STATIC DRAIN-SOURCE ON-STATE RESISTANCE



NOTE A: Technique should limit $T_J - T_C$ to 10°C maximum.

Figure 9

STATIC DRAIN-SOURCE **ON-STATE RESISTANCE**

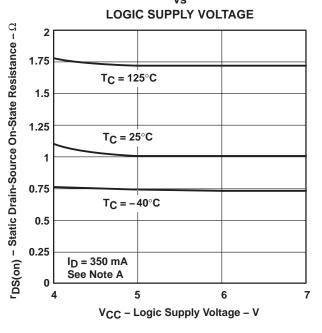
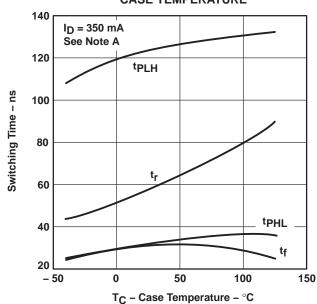


Figure 10



TYPICAL CHARACTERISTICS

SWITCHING TIME vs CASE TEMPERATURE

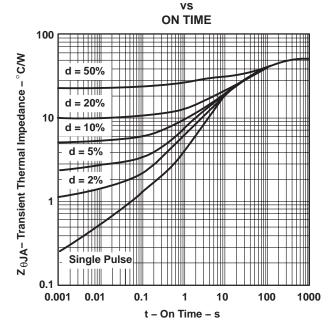


NOTE A: Technique should limit $T_J - T_C$ to 10°C maximum.

Figure 11

THERMAL INFORMATION

NE PACKAGE TRANSIENT THERMAL IMPEDANCE



The single-pulse curve represents measured data. The curves for various pulse durations are based on the following equation:

$$\begin{split} Z_{\theta JA} &= \left| \left| \frac{t_w}{t_c} \right| R_{\theta JA} + \left| 1 - \frac{t_w}{t_c} \right| Z_{\theta}(t_w + t_c) \right. \\ &+ \left. Z_{\theta}(t_w) - Z_{\theta}(t_c) \right. \end{split}$$

Where:

$$Z_{\theta}(t_{w}) =$$
the single-pulse thermal impedance for $t = t_{w}$ seconds

$$Z_{\theta}(t_c) \ = \ \text{the single-pulse thermal impedance} \\ \text{for } t = \ t_c \ \text{seconds}$$

$$\mathbf{Z}_{\theta} \! \left(\mathbf{t_W} \, + \, \mathbf{t_C} \right) \, = \, \, \text{the single-pulse thermal impedance} \\ \quad \text{for } t = \, t_W + t_C \, \text{seconds} \\$$

$$d = t_W/t_C$$

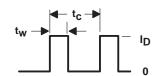


Figure 12





11-Apr-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty		Lead/Ball Finish		Op Temp (°C)	Top-Side Markings	Samples
	(1)		Drawing		Qty	(2)		(3)		(4)	
TPIC6A259DW	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	TPIC6A259	Samples
TPIC6A259DWG4	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	TPIC6A259	Samples
TPIC6A259DWRG4	ACTIVE	SOIC	DW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	TPIC6A259	Samples
TPIC6A259NE	ACTIVE	PDIP	NE	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 125	TPIC6A259NE	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

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⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.





11-Apr-2013

DW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



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